



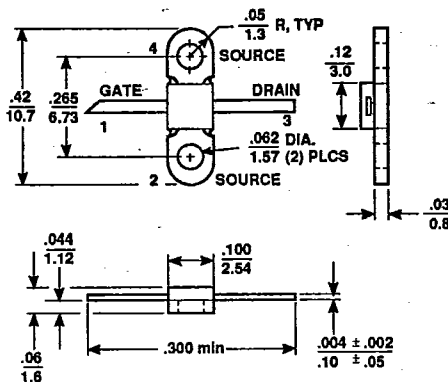
ATF-45101 (AT-8150)
2-8 GHz Medium Power
Gallium Arsenide FET

T-31-25

Features

- High Output Power:
29.0 dBm typical $P_{1\text{ dB}}$ at 4 GHz
- High Gain at 1 dB Compression:
10.0 dB typical $G_{1\text{ dB}}$ at 4 GHz
- High Power Efficiency:
38% typical at 4 GHz
- Hermetic Metal-Ceramic Stripline Package

Avantek 100 mil Flange Package

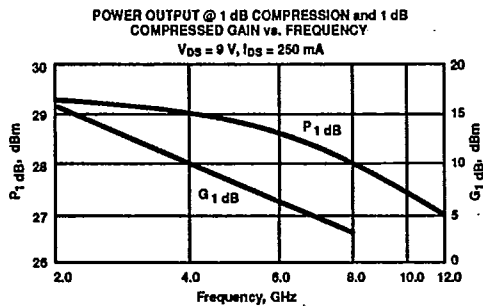


Notes:
(unless otherwise specified)
1. Dimensions are in
mm
2. Tolerances
in .xxx = ±.005
mm .xx = ±.13

Description

The ATF-45101 is a gallium arsenide Schottky-barrier-gate field effect transistor designed for medium power, linear amplification in the 2 to 8 GHz frequency range. This nominally 0.5 micron gate length GaAs FET is an interdigitated four-cell structure using airbridge interconnects between drain fingers. Total gate periphery is 2.5 millimeters. Proven gold based metalization systems and nitride passivation assure a rugged, reliable device.

This device is suitable for applications in space, airborne, military ground and shipboard, and commercial environments. It is supplied in a hermetic high reliability package with low parasitic reactance and minimum thermal resistance.



Electrical Specifications, $T_A = 25^\circ\text{C}$

Symbol	Parameters and Test Conditions	Units	Min.	Typ.	Max.
$P_{1\text{ dB}}$	Output Power @ 1 dB Gain Compression: $V_{DS} = 9\text{ V}$, $I_{DS} = 250\text{ mA}$	f = 4.0 GHz f = 8.0 GHz	dBm	28.0 29.0	28.0
$G_{1\text{ dB}}$	1 dB Compressed Gain: $V_{DS} = 9\text{ V}$, $I_{DS} = 250\text{ mA}$	f = 4.0 GHz f = 8.0 GHz	dB	9.0 10.0	4.0
η_{add}	Efficiency @ $P_{1\text{ dB}}$: $V_{DS} = 9\text{ V}$, $I_{DS} = 250\text{ mA}$	f = 4.0 GHz	%	38	
g_m	Transconductance: $V_{DS} = 2.5\text{ V}$, $I_{DS} = 250\text{ mA}$		mmho	200	
I_{DSS}	Saturated Drain Current: $V_{DS} = 1.75\text{ V}$, $V_{GS} = 0\text{ V}$		mA	400	800
V_p	Pinchoff Voltage: $V_{DS} = 2.5\text{ V}$, $I_{DS} = 5\text{ mA}$		V	-5.4	-4.0

ATF-45101, 2-8 GHz
Medium Power Gallium Arsenide FET

Absolute Maximum Ratings

Parameter	Symbol	Absolute Maximum ¹
Drain-Source Voltage	V _{DS}	+14 V
Gate-Source Voltage	V _{GS}	-7 V
Drain Current	I _{DS}	I _{DSS}
Power Dissipation ^{2,3}	P _T	3.6 W
Channel Temperature	T _{CH}	175°C
Storage Temperature	T _{STG}	-65°C to +175°C

Thermal Resistance: $\theta_{jc} = 42^\circ\text{C/W}$; T_{CH} = 150°C
Liquid Crystal Measurement; 1 μm Spot Size⁴

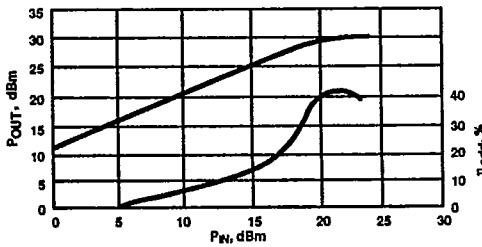
Notes:

1. Operation of this device above any one of these parameters may cause permanent damage.
2. Case Temperature = 25°C.
3. Derate at 24 mW/°C for T_{CASE} > 24°C.
4. The small spot size of this technique results in a higher, though more accurate determination of θ_{jc} than do alternate methods. See MEASUREMENTS section for more information.

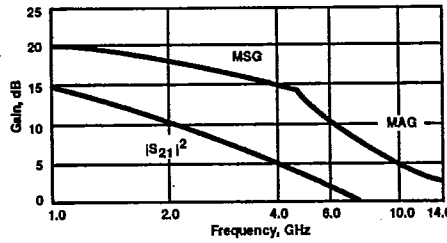
Typical Performance, T_A = 25°C
(unless otherwise noted)

T-31-25

OUTPUT POWER AND POWER ADDED EFFICIENCY
vs. INPUT POWER
V_{DS} = 9 V, I_{DSS} = 250 mA, f = 4.0 GHz



INSERTION POWER GAIN, MAXIMUM AVAILABLE GAIN
AND MAXIMUM STABLE GAIN vs. FREQUENCY
V_{DS} = 9 V, I_{DSS} = 250 mA



Typical Scattering Parameters: Common Source, Z₀ = 50 Ω

T_A = 25°C, V_{DS} = 9 V, I_{DSS} = 250 mA

Freq. GHz	S ₁₁		S ₂₁			S ₁₂			S ₂₂	
	Mag	Ang	dB	Mag	Ang	dB	Mag	Ang	Mag	Ang
1.0	.89	-88	14.9	5.54	119	-26.2	.049	43	.31	-63
2.0	.83	-135	10.8	3.48	82	-26.0	.050	18	.33	-108
3.0	.81	-158	7.6	2.40	58	-25.8	.051	7	.39	-129
4.0	.84	-174	5.4	1.86	38	-25.5	.053	3	.46	-144
5.0	.82	170	3.8	1.55	18	-25.2	.055	-2	.50	-154
6.0	.81	152	2.6	1.36	-2	-24.4	.060	-8	.52	-168
7.0	.81	133	1.2	1.15	-25	-23.9	.064	-15	.55	173
8.0	.81	122	-0.3	.97	-42	-23.5	.067	-20	.59	154
9.0	.80	113	-1.8	.81	-60	-22.6	.074	-31	.64	137
10.0	.79	107	-3.2	.69	-73	-22.0	.079	-40	.68	123
11.0	.77	94	-4.6	.59	-91	-21.5	.084	-45	.72	113
12.0	.73	82	-5.8	.51	-106	-20.3	.097	-55	.76	99
13.0	.68	69	-6.7	.46	-123	-18.3	.121	-63	.78	89
14.0	.64	56	-7.1	.44	-137	-15.9	.161	-79	.80	79

A model for this device is available in the DEVICE MODELS section.